

Search Notes**Application/Control No.**

10/567,479

Examiner

SYED ZAIDI

Applicant(s)/Patent under Reexamination

YAMADA ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
455	566	4/25/2008	SZ
455	567	4/25/2008	SZ
455	575.1	4/25/2008	SZ
379	330	4/25/2008	SZ
379	373.01	4/25/2008	SZ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	4/25/2008	SZ
Inventors : YAMADA ET AL.	4/25/2008	SZ
(IEEE Xplore Database(http://ieeexplore.ieee.org/Xplore/DynWeb.jsp))	4/25/2008	SZ
(455/566 455/567 455/575.1).ccls. (379/330 379/373.01 379/373.02 379/376.01).ccls.	4/25/2008	SZ
Consulted with SPE Nick Corsaro	4/25/2008	SZ